TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 5 2 5 7

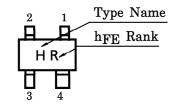
VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

Low Noise Figure : NF=1.5dB (f=2GHz)
 High Gain : Gain=10dB (f=2GHz)

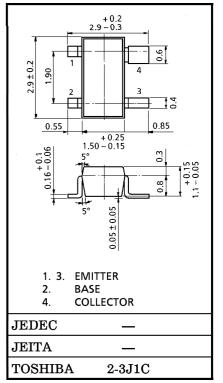
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	15	V
Collector-Emitter Voltage	v_{CEO}	7	V
Emitter-Base Voltage	$v_{ m EBO}$	1.5	V
Collector Current	$I_{\mathbf{C}}$	40	mA
Base Current	I_{B}	20	mA
Collector Power Dissipation	$P_{\mathbf{C}}$	150	mW
Junction Temperature	T_{j}	125	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~125	$^{\circ}\mathrm{C}$

MARKING



Unit in mm



Weight: 0.012g

MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	${ m fT}$	$V_{CE}=5V$, $I_{C}=20mA$	9	12	_	GHz
I Incontion Coin	-	$V_{CE}=5V$, $I_{C}=20mA$, $f=1GHz$	13	16	_	dB
	$ S_{21e} ^2$ (2)	$V_{CE}=5V$, $I_{C}=20mA$, $f=2GHz$	7	10	_	ub
Noise Figure —	NF (1)	$V_{CE}=5V$, $I_{C}=5mA$, $f=1GHz$		1.1		dB
	NF (2)	$V_{CE}=5V$, $I_{C}=5mA$, $f=2GHz$	_	1.5	3	ub

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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = 10V, I_{E} = 0$		_	1	μ A
Emitter Cut-off Current	$I_{ m EBO}$	$V_{EB} = 1V, I_{C} = 0$	_	_	1	μ A
DC Current Gain	hFE (Note 1)	$V_{ m CE}$ =5V, $I_{ m C}$ =20mA	50	_	160	_
Output Capacitance	C_{ob}	$V_{\mathrm{CB}} = 5 \mathrm{V}, \ \mathrm{I_E} = 0, \ \mathrm{f} = 1 \mathrm{MHz}$		0.6	_	pF
Reverse Transfer Capacitance	$\mathrm{C_{re}}$	(Note 2)		0.45	0.85	pF

(Note 1): hFE Classification $R:50{\sim}100,~O:80{\sim}160$ (Note 2): C_{re} is measured by 3 terminal method with capacitance bridge.

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